# RENESAS

# **R1LV1616HSA-I Series**

Wide Temperature Range Version 16 M SRAM (1-Mword × 16-bit / 2-Mword × 8-bit)

> REJ03C0195-0102 Rev. 1.02 Feb.23.2017

#### Description

The R1LV1616HSA-I Series is 16-Mbit static RAM organized 1-Mword  $\times$  16-bit / 2-Mword  $\times$  8-bit with embedded ECC. R1LV1616HSA-I Series has realized higher density, higher performance and low power consumption by employing CMOS process technology (6-transistor memory cell). It offers low power standby power dissipation; therefore, it is suitable for battery backup systems. It is packaged in 48-pin plastic TSOPI for high density surface mounting.

#### Features

- Single 3.0 V supply: 2.7 V to 3.6 V
- Fast access time: 45/55 ns (max)
- Power dissipation:
  - Active: 9 mW/MHz (typ)
  - Standby:  $1.5 \mu W$  (typ)
- Completely static memory.
  - No clock or timing strobe required
- Equal access and cycle times
- Common data input and output.
  - Three state output
- Battery backup operation.
  - 2 chip selection for battery backup
- Temperature range: -40 to +85°C
- Byte function (x8 mode) available by BYTE# & A-1
- Embedded ECC (error checking and correction) for single-bit error correction



## **Ordering Information**

Type No.	Access time	Package
R1LV1616HSA-4SI	45 ns	48-pin plastic TSOPI
R1LV1616HSA-5SI	55 ns	



## **Pin Arrangement**





## **Pin Description** (TSOP)

Pin name	Function
A0 to A19	Address input (word mode)
A-1 to A19	Address input (byte mode)
I/O0 to I/O15	Data input/output
CS1# ( <del>CS1</del> )	Chip select 1
CS2	Chip select 2
WE# (WE)	Write enable
OE# (OE)	Output enable
LB# (LB)	Lower byte select
UB# (UB)	Upper byte select
BYTE# (BYTE)	Byte enable
Vcc	Power supply
Vss	Ground
NC	No connection
NU*1	Not used (test mode pin)

Note: 1. This pin should be connected to a ground (Vss), or not be connected (open).



#### **Block Diagram (TSOP)**



## **Operation Table** (TSOP)

#### Byte mode

CS1#	CS2	WE#	OE#	UB#	LB#	BYTE#	I/O0 to I/O7	I/O8 to I/O14	I/O15	Operation
Н	×	×	×	×	×	L	High-Z	High-Z	High-Z	Standby
×	L	×	×	×	×	L	High-Z	High-Z	High-Z	Standby
L	Н	Н	L	×	×	L	Dout	High-Z	A-1	Read
L	Н	L	×	×	×	L	Din	High-Z A-1		Write
L	Н	Н	Н	×	×	L	High-Z	High-Z	High-Z	Output disable

Note: H: V<sub>IH</sub>, L: V<sub>IL</sub>,  $\times$ : V<sub>IH</sub> or V<sub>IL</sub>

#### Word mode

CS1#	CS2	WE#	OE#	UB#	LB#	BYTE#	I/O0 to I/O7	I/O8 to I/O14	I/O15	Operation
Н	×	×	×	×	×	Н	High-Z	High-Z High-Z High-Z		Standby
×	L	×	×	×	×	Н	High-Z	High-Z	High-Z	Standby
×	×	×	×	Н	Н	Н	High-Z	High-Z High-Z High-Z		Standby
L	Н	Н	L	L	L	Н	Dout Dout		Dout	Read
L	Н	Н	L	Н	L	Н	Dout	High-Z	High-Z	Lower byte read
L	Н	Н	L	L	Н	Н	High-Z	Dout	Dout	Upper byte read
L	Н	L	×	L	L	Н	Din	Din	Din	Write
L	Н	L	×	Н	L	Н	Din	High-Z	High-Z	Lower byte write
L	Н	L	×	L	Н	Н	High-Z	Din	Din	Upper byte write
L	Н	Н	Н	×	×	Н	High-Z	High-Z	High-Z	Output disable

Note: H: VIH, L: VIL, X: VIH or VIL



## **Absolute Maximum Ratings**

Parameter	Symbol	Value	Unit
Power supply voltage relative to Vss	Vcc	–0.5 to +4.6	V
Terminal voltage on any pin relative to $V_{SS}$	VT	-0.5*1 to V <sub>CC</sub> + 0.3*2	V
Power dissipation	PT	1.0	W
Storage temperature range	Tstg	-55 to +125	°C
Storage temperature range under bias	Tbias	-40 to +85	°C

Notes: 1.  $V_T$  min: -2.0 V for pulse half-width  $\leq$  10 ns.

2. Maximum voltage is +4.6 V.

## **DC Operating Conditions**

Parameter	Symbol	Min	Тур	Max	Unit	Note
Supply voltage	Vcc	2.7	3.0	3.6	V	
	Vss	0	0	0	V	
Input high voltage	VIH	2.2	_	V <sub>CC</sub> + 0.3	V	
Input low voltage	VIL	-0.3	_	0.6	V	1
Ambient temperature range	Та	-40		+85	°C	

Note: 1.  $V_{IL}$  min: -2.0 V for pulse half-width  $\leq$  10 ns.



## **DC** Characteristics

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions*2
Input leakage current	lu			1	μA	Vin = Vss to Vcc
Output leakage current	Ilo	_		1	μA	$\begin{array}{l} CS1\# = V_{IH} \text{ or } CS2 = V_{IL} \text{ or} \\ OE\# = V_{IH} \text{ or } WE\# = V_{IL} \text{ or} \\ LB\# = UB\# = V_{IH}, V_{I/O} = V_{SS} \text{ to } V_{CC} \end{array}$
Operating current	lcc	_	—	20	mA	$\label{eq:cs1} \begin{split} &CS1\#=V_{IL},CS2=V_{IH},\\ &Others=V_{IH}/V_{IL},I_{I/O}=0\text{mA} \end{split}$
Average operating current	I <sub>CC1</sub> (READ)	_	22* <sup>1</sup>	35	mA	
	Icc1	—	30* <sup>1</sup>	50	mA	
	Icc2*3 (READ)		3*1	8	mA	$ \begin{array}{l} Cycle time = 70 \text{ ns, } duty = 100\%, \\ I_{I/O} = 0 \text{ mA, } CS1\# = V_{IL}, \ CS2 = V_{IH}, \\ WE\# = V_{IH}, \ Others = V_{IH}/V_{IL} \\ Address increment scan or \\ decrement scan \end{array} $
	Icc2*3		20*1	30	mA	$ \begin{array}{l} Cycle time = 70 \text{ ns, } duty = 100\%, \\ I_{I/O} = 0 \text{ mA, } CS1\# = V_{IL}, CS2 = V_{IH}, \\ Others = V_{IH}/V_{IL} \\ Address increment scan or \\ decrement scan \end{array} $
	Іссз		3*1	8	mA	$\begin{array}{l} \mbox{Cycle time = 1 } \mu s, \mbox{ duty = 100\%,} \\ I_{I/O} = 0 \mbox{ mA, CS1\# $\le$ 0.2 V,} \\ \mbox{CS2 $\ge$ $V_{CC} - 0.2 V$} \\ \mbox{V}_{IH} \ge \mbox{V}_{CC} - 0.2 \mbox{ V, } \mbox{V}_{IL} \le 0.2 \mbox{ V} \end{array}$
Standby current	Isb		0.1* <sup>1</sup>	0.5	mA	CS2 = VIL
Standby current	Isb1		0.5*1	8	μA	$\begin{array}{l} 0 \ V \leq & \overline{Vin} \\ (1) \ 0 \ V \leq & CS2 \leq 0.2 \ V \ or \\ (2) \ CS1\# \geq V_{CC} - 0.2 \ V, \\ CS2 \geq V_{CC} - 0.2 \ V \ or \\ (3) \ LB\# = UB\# \geq V_{CC} - 0.2 \ V, \\ CS2 \geq V_{CC} - 0.2 \ V, \\ CS1\# \leq 0.2 \ V \\ Average \ value \end{array}$
Output high voltage	Vон	2.4			V	I <sub>ОН</sub> = –1 mA
	Voh	Vcc - 0.2			V	Іон = –100 μА
Output low voltage	Vol			0.4	V	I <sub>OL</sub> = 2 mA
	Vol			0.2	V	Ιοι = 100 μΑ

Notes: 1. Typical values are at  $V_{CC}$  = 3.0 V, Ta = +25°C and not guaranteed.

- 2. BYTE#  $\geq$  Vcc 0.2 V or BYTE#  $\leq$  0.2 V
- I<sub>CC2</sub> is the value measured while the valid address is increasing or decreasing by one bit. Word mode: LSB (least significant bit) is A0. Byte mode: LSB (least significant bit) is A-1.

#### Capacitance

 $(Ta = +25^{\circ}C, f = 1.0 \text{ MHz})$ 

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions	Note
Input capacitance	Cin			8	pF	Vin = 0 V	1
Input/output capacitance	Cı/o	_		10	pF	$V_{I/O} = 0 V$	1

Note: 1. This parameter is sampled and not 100% tested.



#### **AC Characteristics**

 $(Ta = -40 \text{ to } +85^{\circ}\text{C}, V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}, \text{ unless otherwise noted.})$ 

#### **Test Conditions**

- Input pulse levels:  $V_{IL} = 0.4 \text{ V}$ ,  $V_{IH} = 2.4 \text{ V}$
- Input rise and fall time: 5 ns
- Input and output timing reference levels: 1.4 V
- Output load: See figures (Including scope and jig)





## Read Cycle

			R1LV16	16HSA-I			
		-4	-4SI		SI		
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Read cycle time	t <sub>RC</sub>	45	_	55	_	ns	
Address access time	taa		45		55	ns	
Chip select access time	t <sub>ACS1</sub>		45		55	ns	
	t <sub>ACS2</sub>		45		55	ns	
Output enable to output valid	toe		30		35	ns	
Output hold from address change	toн	10		10		ns	
LB#, UB# access time	t <sub>BA</sub>		45		55	ns	
Chip select to output in low-Z	t <sub>CLZ1</sub>	10	_	10	_	ns	2, 3
	t <sub>CLZ2</sub>	10		10		ns	2, 3
LB#, UB# enable to low-Z	t <sub>BLZ</sub>	5		5		ns	2, 3
Output enable to output in low-Z	tolz	5		5		ns	2, 3
Chip deselect to output in high-Z	t <sub>CHZ1</sub>	0	20	0	20	ns	1, 2, 3
	t <sub>CHZ2</sub>	0	20	0	20	ns	1, 2, 3
LB#, UB# disable to high-Z	tвнz	0	15	0	20	ns	1, 2, 3
Output disable to output in high-Z	tонz	0	15	0	20	ns	1, 2, 3

## Write Cycle

			R1LV16	16HSA-I			
		-4	SI	-5	SI		
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Write cycle time	twc	45		55		ns	
Address valid to end of write	t <sub>AW</sub>	45		50		ns	
Chip selection to end of write	t <sub>CW</sub>	45		50		ns	5
Write pulse width	t <sub>WP</sub>	35		40		ns	4
LB#, UB# valid to end of write	t <sub>BW</sub>	45		50		ns	
Address setup time	tas	0		0		ns	6
Write recovery time	twR	0		0		ns	7
Data to write time overlap	t <sub>DW</sub>	25		25		ns	
Data hold from write time	t <sub>DH</sub>	0		0		ns	
Output active from end of write	t <sub>ow</sub>	5		5		ns	2
Output disable to output in high-Z	tонz	0	15	0	20	ns	1, 2
Write to output in high-Z	t <sub>wнz</sub>	0	15	0	20	ns	1, 2

#### **Byte Control**

			R1LV1616HSA-I				
		-4	SI	-5	SI		
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
BYTE# setup time	t <sub>BS</sub>	5	_	5	_	ms	
BYTE# recovery time	t <sub>BR</sub>	5		5		ms	

Notes: 1. t<sub>CHZ</sub>, t<sub>OHZ</sub>, t<sub>WHZ</sub> and t<sub>BHZ</sub> are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.

- 2. This parameter is sampled and not 100% tested.
- 3. At any given temperature and voltage condition,  $t_{HZ}$  max is less than  $t_{LZ}$  min both for a given device and from device to device.
- 4. A write occurs during the overlap of a low CS1#, a high CS2, a low WE# and a low LB# or a low UB#. A write begins at the latest transition among CS1# going low, CS2 going high, WE# going low and LB# going low or UB# going low. A write ends at the earliest transition among CS1# going high, CS2 going low, WE# going high and LB# going high or UB# going high. twp is measured from the beginning of write to the end of write.
- 5.  $t_{CW}$  is measured from the later of CS1# going low or CS2 going high to the end of write.
- 6.  $t_{AS}$  is measured from the address valid to the beginning of write.
- 7.  $t_{WR}$  is measured from the earliest of CS1# or WE# going high or CS2 going low to the end of write cycle.



## **Timing Waveform**

Read Cycle\*1



#### Write Cycle (1)\*<sup>1</sup> (WE# Clock)





Write Cycle (2)\*1 (CS1#, CS2 Clock,  $OE# = V_{IH}$ )

Write Cycle (3)\*1 (LB#, UB# Clock,  $OE# = V_{IH}$ )



#### **Byte Control** (TSOP)





#### Low V<sub>CC</sub> Data Retention Characteristics

 $(Ta = -40 \text{ to } +85^{\circ}\text{C})$ 

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions* <sup>2, 3</sup>
V <sub>CC</sub> for data retention	V <sub>DR</sub>	1.5	_	3.6	V	$ \begin{array}{l} \mbox{Vin} \geq 0 \ \mbox{V} \\ (1) \ 0 \ \mbox{V} \leq CS2 \leq 0.2 \ \mbox{V or} \\ (2) \ CS2 \geq V_{CC} - 0.2 \ \mbox{V}, \\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ $
Data retention current	ICCDR		0.5*1	8	μA	$\begin{array}{l} V_{CC} = 3.0 \ V, \ Vin \geq 0 \ V \\ (1) \ 0 \ V \leq CS2 \leq 0.2 \ V \ or \\ (2) \ CS2 \geq V_{CC} - 0.2 \ V, \\ \ CS1 \# \geq V_{CC} - 0.2 \ V \ or \\ (3) \ LB\# = UB\# \geq V_{CC} - 0.2 \ V, \\ \ CS2 \geq V_{CC} - 0.2 \ V, \\ \ CS1 \# \leq 0.2 \ V \\ Average \ value \end{array}$
Chip deselect to data retention time	t <sub>CDR</sub>	0			ns	See retention waveforms
Operation recovery time	t <sub>R</sub>	5			ms	]

Notes: 1. Typical values are at  $V_{CC}$  = 3.0 V, Ta = +25°C and not guaranteed.

2. BYTE#  $\geq V_{CC} - 0.2$  V or BYTE#  $\leq 0.2$  V

3. CS2 controls address buffer, WE# buffer, CS1# buffer, OE# buffer, LB#, UB# buffer and Din buffer. If CS2 controls data retention mode, Vin levels (address, WE#, OE#, CS1#, LB#, UB#, I/O) can be in the high impedance state. If CS1# controls data retention mode, CS2 must be  $CS2 \ge V_{CC} - 0.2 \text{ V}$  or  $0 \text{ V} \le CS2 \le 0.2 \text{ V}$ . The other input levels (address, WE#, OE#, LB#, UB#, I/O) can be in the high impedance state.







Low V<sub>CC</sub> Data Retention Timing Waveform (2) (CS2 Controlled)



Low Vcc Data Retention Timing Waveform (3) (LB#, UB# Controlled)



## **Revision History**

## R1LV1616HSA-I Series Data Sheet

Rev.	Date	Contents of Modification	
		Page	Description
1.00	Apr.22.2004	—	Initial issue
1.01	Nov.18.2004	—	Addition of 2-Mword x 8-bit function
1.02	Feb.23.2017	p.1,p.5	Disclosed embedded ECC features
		p.2	Deleted previous package code (48P3R-B)

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